

Amendments to the Claims

The following listing of claims will replace all prior versions and/or listings of claims in the application:

1. (Currently amended): A probe coming into contact with an electrode pad of a measurement object, comprising:

a connection terminal part integrally formed and connected to a substrate;

a probe support portion; and

a contact part, the contact part comprising

an edge part part having a tapered end configuration; and

a supporting-part contact support part which supports the contact part edge part and couples the edge part to the probe support part,

wherein the contact part extending extends from an end of the the probe supporting part support part, and wherein the edge part has a sectional configuration which shares at least one side face with the supporting-part contact support part and wherein the edge part has a thickness that is less than the thickness of the contact support part.

2. (Original): The probe according to claim 1, wherein the contact part is formed of an electrically conductive material having superior electric characteristics.

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3. (Original): The probe according to claim 1, wherein the contact part is formed of a metal material having elasticity.